

Product Specification

N-Channel Enhancement Mode Power MOSFET

MS4N65

•Description

The MS4N65 is a N-channel enhancement-mode MOSFET, providing the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness. The TO-220 package is universally preferred for all commercial-industrial applications

•FEATURES:

- BVDSS=650V typically @ Tj=150°C
- Low On Resistance
- Simple Drive Requirement
- Low Gate Charge
- Fast Switching Characteristic
- RoHS compliant package

•APPLICATION:

- Open Framed Power Supply
- Adapter
- STB

BVDSS : 650V
RDS(ON) : 2.4Ω(typ.)
ID : 3.6A

TO-220



1.Gate 2. Drain 3. Source

Absolute Maximum Ratings

Symbol	Parameter	Value	Units
V _{DSS}	Drain to Source Voltage	650	V
V _{GS}	Gate to Source Voltage	±30	V
I _D	Continuous Drain Current(@T _C = 25 °C)	3.6	A
	Continuous Drain Current(@T _C = 100 °C)	2.3	A
I _{DM}	Drain Current Pulsed	16.4	A
E _{AS}	Single Pulsed Avalanche Energy	240	mJ
E _{AR}	Repetitive Avalanche Energy	10	mJ
dv/dt	Peak Diode Recovery dv/dt	5.5	V/ns
T _L	Maximum Temperature for Soldering @ Lead at 0.125 in(0.318mm) from case for 10 seconds	300	°C
T _{PKG}	Maximum Temperature for Soldering @ Package Body for 10 seconds	260	°C
P _D	Total Power Dissipation(@T _C = 25 °C)	100	W
	Derating Factor above 25 °C	0.8	W/°C
T _{STG}	Operating Junction Temperature	-55 ~ 150	°C
T _J	Storage Temperature	150	°C

Note:

1. Repetitive rating; pulse width limited by maximum junction temperature.
2. IAS=4A, VDD=50V, L=8mH, VG=10V, starting TJ=+25°C.
3. ISD≤4A, di/dt≤100A/μs, VDD≤BVDSS, starting TJ=+25°C.

Thermal Characteristics

Symbol	Parameter	Value			Units
		Min.	Typ.	Max.	
R _{θJC}	Thermal Resistance, Junction-to-Case	-	-	1.25	°C/W
R _{θJA}	Thermal Resistance, Junction-to-Ambient	-	-	62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	650	-	-	V
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temperature coefficient	$I_D = 250\text{ }\mu\text{A}$, referenced to $25\text{ }^\circ\text{C}$	-	0.60	-	V/ $^\circ\text{C}$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$	2.0	-	4.0	V
I_{DSS}	Drain-Source Leakage Current	$V_{DS} = 650\text{ V}$, $V_{GS} = 0\text{ V}$	-	-	1	μA
		$V_{DS} = 520\text{ V}$, $T_C = 125\text{ }^\circ\text{C}$	-	-	10	nA
I_{GSS}	Gate-Source Leakage, Forward	$V_{GS} = \pm 30$	-	-	100	nA
$R_{DS(ON)}$	Static Drain-Source On-state Resistance	$V_{GS} = 10\text{ V}$, $I_D = 1.8\text{ A}$	-	2.4	2.9	Ω
Dynamic Characteristics						
Q_g	Total Gate Charge	$V_{DS} = 520\text{ V}$, $V_{GS} = 10\text{ V}$, $I_D = 3.6\text{ A}$	-	15	20	nC
Q_{gs}	Gate-Source Charge		-	2.8	-	
Q_{gd}	Gate-Drain Charge(Miller Charge)		-	6.0	-	
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 325\text{ V}$, $I_D = 3.6\text{ A}$, $V_{GS} = 10\text{ V}$, $R_G = 25\Omega$, $R_D = 75\Omega$	-	10	30	ns
t_r	Rise Time		-	35	80	
$t_{d(off)}$	Turn-off Delay Time		-	45	100	
t_f	Fall Time		-	40	90	
C_{iss}	Input Capacitance	$V_{GS} = 0\text{ V}$, $V_{DS} = 25\text{ V}$, $f = 1\text{ MHz}$	-	560	-	pF
C_{oss}	Output Capacitance		-	55	-	
C_{rss}	Reverse Transfer Capacitance		-	7	-	

• Characteristic Curves

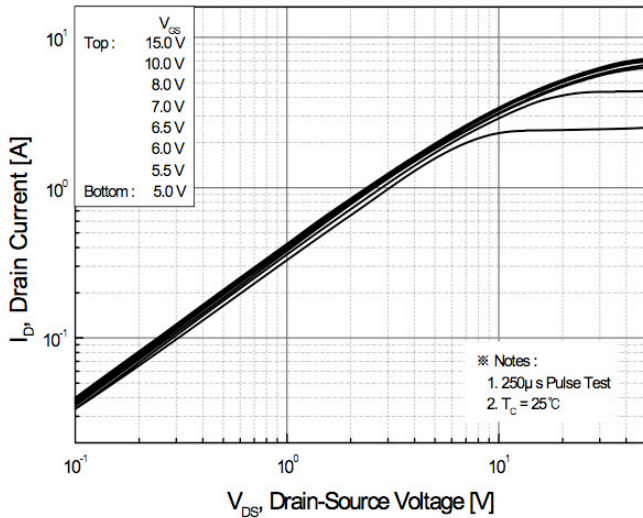


Figure 1. On Region Characteristics

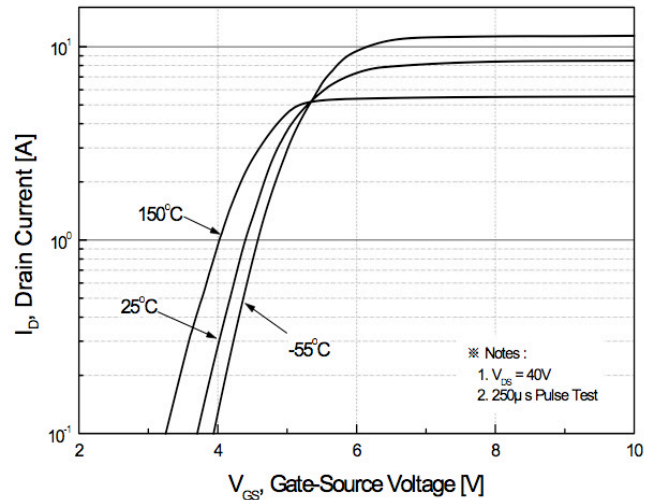


Figure 2. Transfer Characteristics

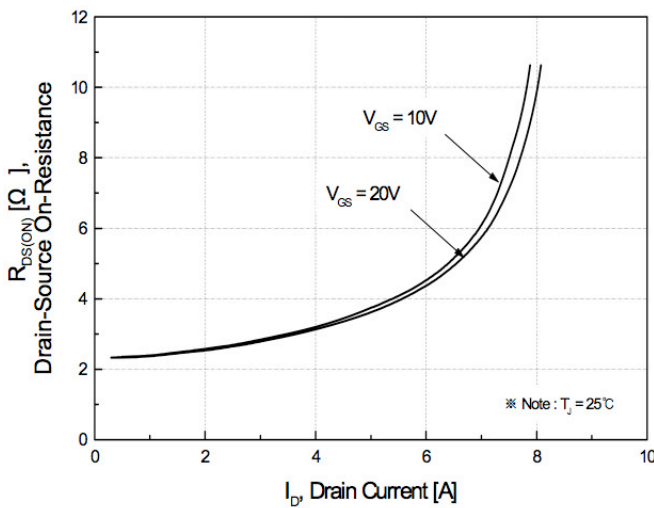


Figure 3. On Resistance Variation vs Drain Current and Gate Voltage

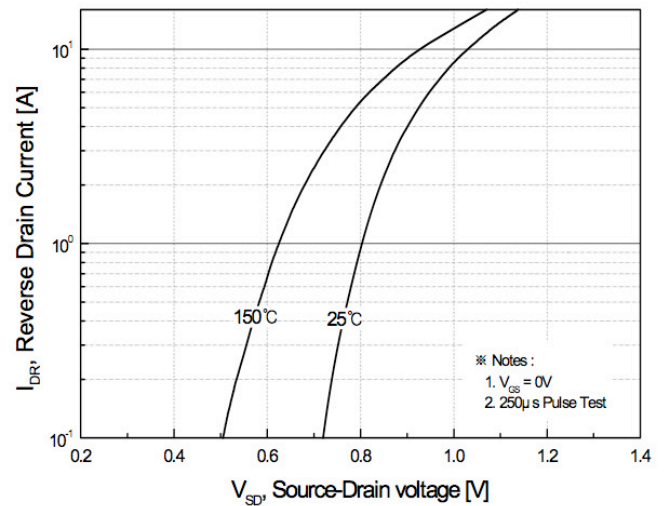


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

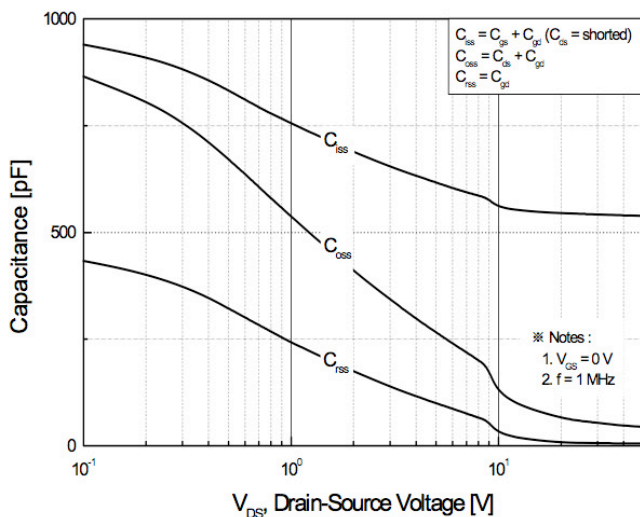


Figure 5. Capacitance Characteristics

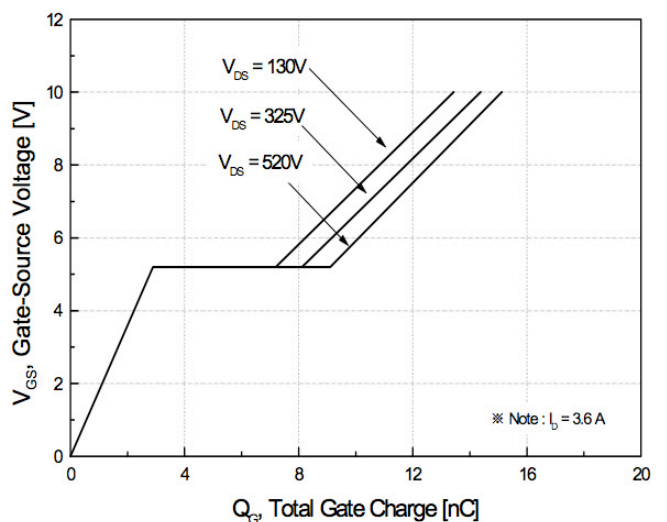


Figure 6. Gate Charge Characteristics

• Characteristic Curves

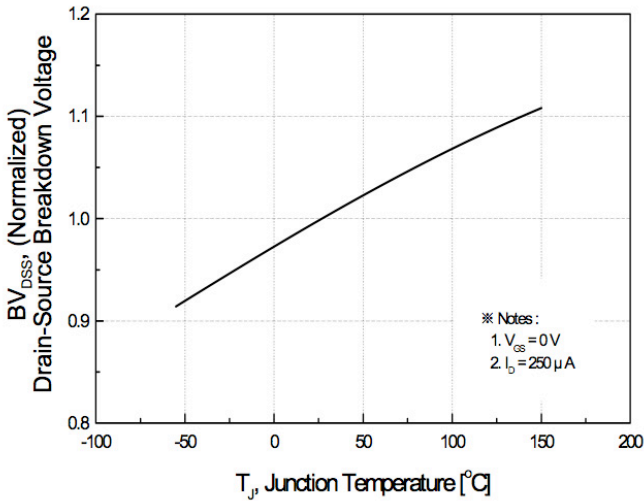


Figure 7. Breakdown Voltage Variation vs. Temperature

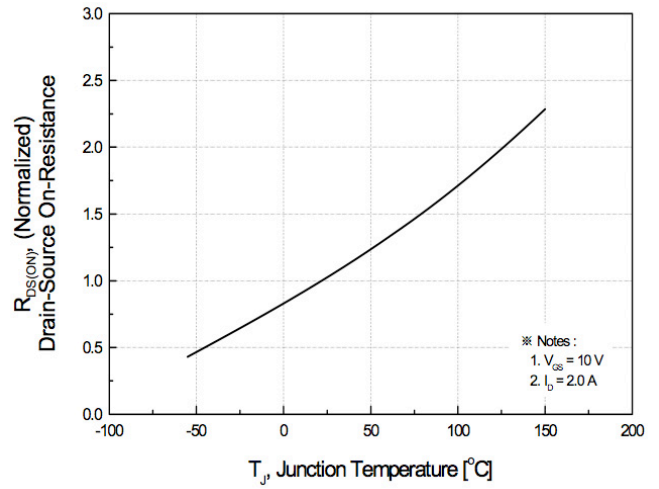


Figure 8. On-Resistance Variation vs. Temperature

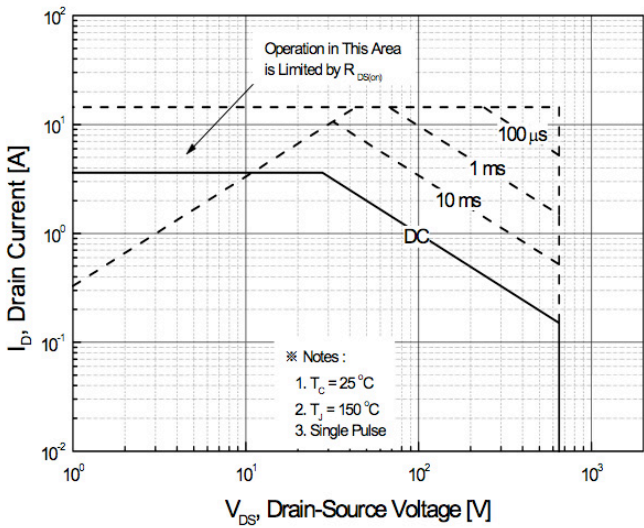


Figure 9. Maximum Safe Operating Area

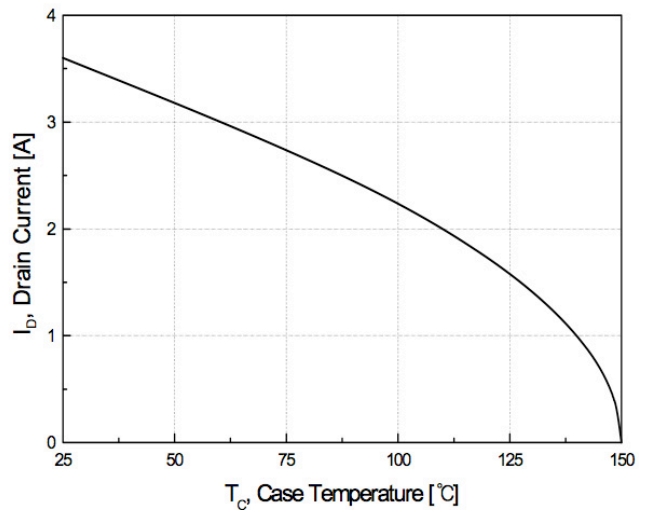


Figure 10. Maximum Drain Current vs. Case Temperature

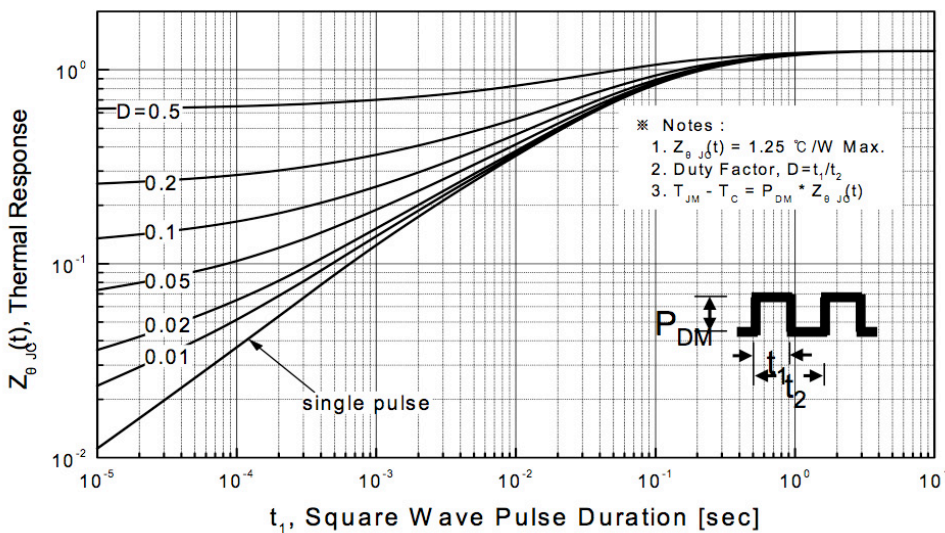


Figure 11. Transient Thermal Response Curve